

Is Now Part of



ON Semiconductor®

To learn more about ON Semiconductor, please visit our website at <u>www.onsemi.com</u>

Please note: As part of the Fairchild Semiconductor integration, some of the Fairchild orderable part numbers will need to change in order to meet ON Semiconductor's system requirements. Since the ON Semiconductor product management systems do not have the ability to manage part nomenclature that utilizes an underscore (_), the underscore (_) in the Fairchild part numbers will be changed to a dash (-). This document may contain device numbers with an underscore (_). Please check the ON Semiconductor website to verify the updated device numbers. The most current and up-to-date ordering information can be found at www.onsemi.com. Please email any questions regarding the system integration to Fairchild_questions@onsemi.com.

ON Semiconductor and the ON Semiconductor logo are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor products for any such unintended or unauthorized applications, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that ON Semiconductor was negligent regarding the design or manufacture of the part. ON Semiconductor is an ad experson



N-Channel SupreMOS[®] MOSFET

600 V, 22 A, 165 m Ω

Features

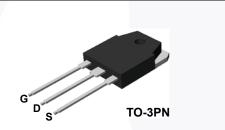
- BV_{DSS} > 650 V @ T_J = 150°C
- $R_{DS(on)}$ = 140 m Ω (Typ.) @ V_{GS} = 10 V, I_D = 11 A
- Ultra Low Gate Charge (Typ. Q_g = 45 nC)
- Low Effective Output Capacitance (Typ. C_{oss(eff.)} = 196.4 pF)
- 100% Avalanche Tested
- RoHS Compliant

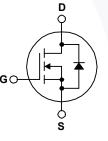
Application

- PDP TV
- Solar Inverter
- AC-DC Power Supply

Description

The SupreMOS[®] MOSFET is Fairchild Semiconductor's next generation of high voltage super-junction (SJ) technology employing a deep trench filling process that differentiates it from the conventional SJ MOSFETs. This advanced technology and precise process control provides lowest Rsp on-resistance, superior switching performance and ruggedness. SupreMOS MOSFET is suitable for high frequency switching power converter applications such as PFC, server/telecom power, FPD TV power, ATX power, and industrial power applications.





MOSFET Maximum Ratings T_C = 25°C unless otherwise noted.

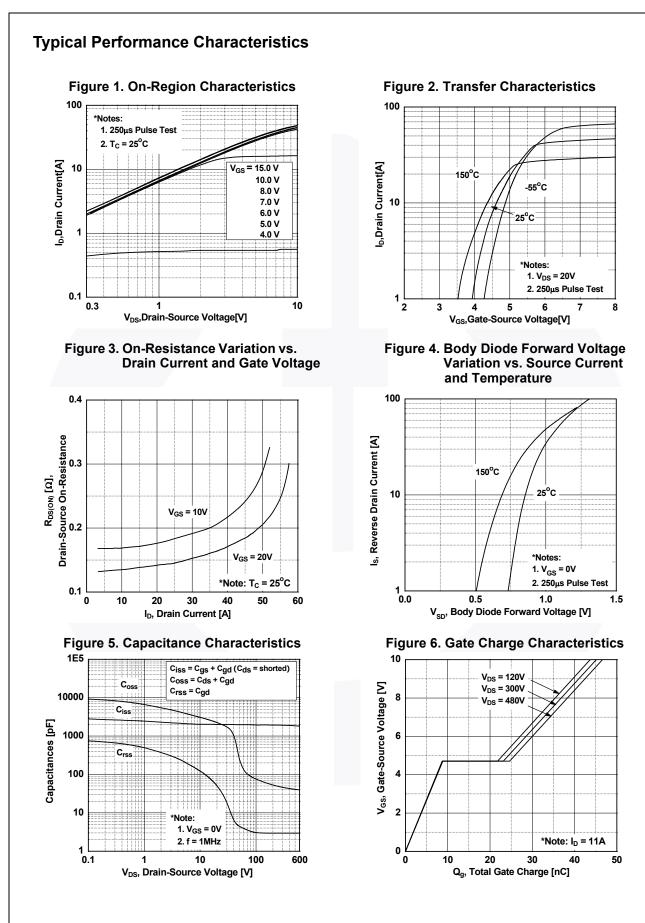
Symbol		FCA22N60N	Unit			
V _{DSS}	Drain to Source Voltage	600	V			
V _{GSS}	Gate to Source Voltage			±30	V	
I _D	Drain Current	- Continuous (T _C = 25 ^o C)		22	Α	
		- Continuous (T _C = 100 ^o C)	- Continuous (T _C = 100 ^o C)			
I _{DM}	Drain Current	- Pulsed	(Note 1)	66	А	
E _{AS}	Single Pulsed Avalanche	(Note 2)	672	mJ		
I _{AR}	Avalanche Current		(Note 1)	7.3	Α	
E _{AR}	Repetitive Avalanche Ene	ergy	(Note 1)	2.75	mJ	
dv/dt	MOSFET dv/dt		100	1//20		
	Peak Diode Recovery dv/dt (Note 3)			20	V/ns	
P _D	Power Dissipation	$(T_{\rm C} = 25^{\rm o}{\rm C})$		205	W	
		- Derate Above 25°C		1.64	W/ºC	
T _J , T _{STG}	Operating and Storage Temperature Range			-55 to +150	°C	
TL	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 Seconds			300	°C	

Thermal Characteristics

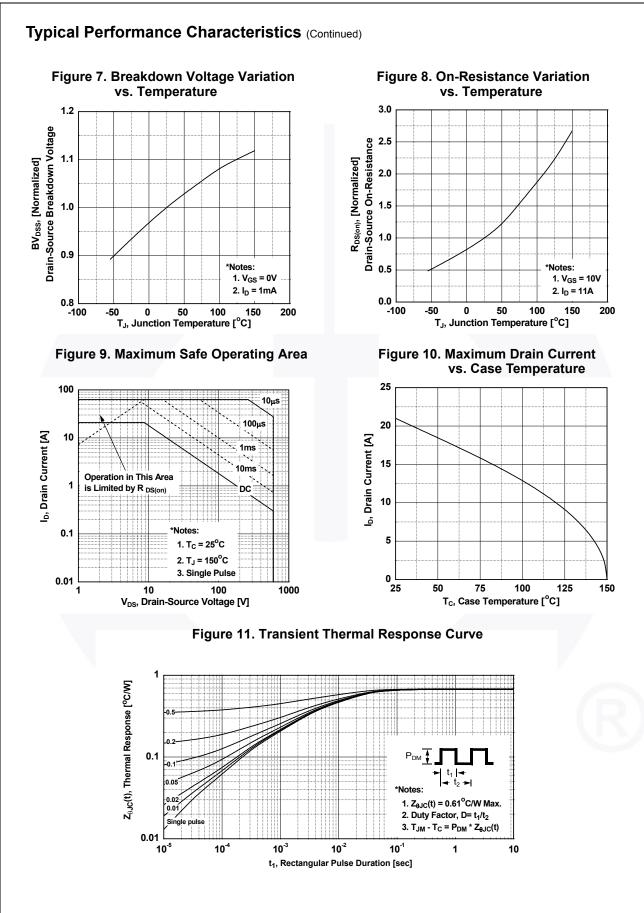
Symbol	Parameter	FCA22N60N	Unit		
$R_{ ext{ heta}JC}$	Thermal Resistance, Junction to Case, Max.	0.61	°C/W		
$R_{ extsf{ heta}JA}$	Thermal Resistance, Junction to Ambient, Max.	40	- °C/W		

	Top Mark	Package	Packing Method	Reel Size	Тар	e Width	Qua	ntity
		TO-3PN	Tube	N/A		N/A	30 units	
Chara	cteristics To = 25%	C unless o	therwise noted.					
Symbol Parameter			Test Conditions		Min.	Тур.	Max.	Unit
teristics	i							
Drain to Source Breakdown Voltage			$\frac{I_{D} = 1 \text{ mA}, V_{GS} = 0 \text{ V}, T_{J} = 25^{\circ}\text{C}}{I_{D} = 1 \text{ mA}, V_{GS} = 0 \text{ V}, T_{J} = 150^{\circ}\text{C}}$		600	-	-	V
					650	-	-	
Breakdown Voltage Temperature Coefficient			$I_D = 1$ mA, Referenced to 25°C		-	0.68	-	V/ºC
Zero Gate Voltage Drain Current			V _{DS} = 480 V, T _J = 125°C		-		-	μA
Gale to Body Leakage Current			$v_{\rm GS} = \pm 30$ V, $v_{\rm DS} = 0$	v	-	-	100	nA
eristics								
Gate Threshold Voltage		١	V _{GS} = V _{DS} , I _D = 250 μA			3	4.0	V
Static Drain to Source On Resistance			$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 11 \text{ A}$		-	0.140	0.165	Ω
Forward	Transconductance	١	V _{DS} = 20 V, I _D = 11 A		-	22	-	S
haracte	ristics							
Input Car	pacitance		$V_{\rm DS} = 100 \text{ V}, \text{ V}_{\rm GS} = 0 \text{ V},$		-	1950	-	pF
Output C	apacitance				-	75.9	-	pF
Reverse Transfer Capacitance		T			-	3	-	pF
Output Capacitance		١	V _{DS} = 380 V, V _{GS} = 0 V, f = 1 MHz		-	43.2	-	pF
Effective Output Capacitance			V _{DS} = 0 V to 480 V, V _{GS} = 0 V		-	196.4	-	pF
Total Gat	e Charge at 10V	\ \	V _{DS} = 380 V, I _D = 11 A, V _{GS} = 10 V		-	45	-	nC
Gate to S	Source Gate Charge				-	8.7	-	nC
Gate to D	Drain "Miller" Charge			(Note 4)	-	14.5	-	nC
Equivaler	nt Series Resistance (G-S)	f	= 1 MHz		-	1	-	Ω
Characte	eristics							
Turn-On	Delay Time				-	16.9	-	ns
Turn-On	Rise Time	١	$V_{DD} = 380 \text{ V}, \text{ I}_{D} = 11 \text{ A},$ $V_{GS} = 10 \text{ V}, \text{ R}_{G} = 4.7 \Omega$ (Note 4)		-	16.7	-	ns
Turn-Off	Delay Time	1			-	49	-	ns
Turn-Off	Fall Time				-	4	-	ns
ce Diod	e Characteristics							
Maximum Continuous Drain to Source Diode Forward Current					-	-	22	Α
			Forward Current		-	-	66	Α
Drain to Source Diode Forward Voltage		age \	V _{GS} = 0 V, I _{SD} = 11 A		-	-	1.2	V
Reverse	Recovery Time	١	V _{GS} = 0 V, I _{SD} = 11 A, dI _F /dt = 100 A/μs		-	350	-	ns
Reverse	Recovery Charge	c			-	6	-	μC
	eristics Drain to S Breakdow Coefficie Zero Gat Gate to E eristics Gate Thr Static Dr Forward haracter Input Cap Output C Effective Total Gat Gate to D Equivaler Character Turn-On Turn-Off Turn-Off Turn-Off Maximum Drain to S	Parameter Drain to Source Breakdown Voltage Breakdown Voltage Temperature Coefficient Zero Gate Voltage Drain Current Gate to Body Leakage Current Cate to Body Leakage Current Cate Threshold Voltage Static Drain to Source On Resistance Forward Transconductance Paracteristics Input Capacitance Output Capacitance Output Capacitance Effective Output Capacitance Cotal Gate Charge at 10V Gate to Source Gate Charge Gate to Drain "Miller" Charge Equivalent Series Resistance (G-S) Characteristics Turn-On Delay Time Turn-Off Delay Time Turn-Off Fall Time Ce Diode Characteristics Maximum Continuous Drain to Source D	Parameter eristics Drain to Source Breakdown Voltage Breakdown Voltage Temperature Coefficient Zero Gate Voltage Drain Current Gate to Body Leakage Current eristics Gate Threshold Voltage Static Drain to Source On Resistance Forward Transconductance Naracteristics Input Capacitance Output Capacitance Output Capacitance Output Capacitance Output Capacitance Output Capacitance Gate to Dourge Gate Charge Gate to Dourge Time Turn-On Delay Time Turn-On Rise Time Turn-Off Fall Time Ce Diode Characteristics Maximum Continuous Drain to Source Diode Forw Drain to Source Diode Forward Voltage	PeristicsDrain to Source Breakdown Voltage $I_D = 1 \text{ mA}, V_{GS} = 0 \text{ V}, T_{I_D} = 1 \text{ mA}, V_{GS} = 0 \text{ V}, T_{I_D} = 1 \text{ mA}, V_{GS} = 0 \text{ V}, T_{I_D} = 1 \text{ mA}, ReferencedZero Gate Voltage Drain CurrentV_{DS} = 480 \text{ V}, V_{GS} = 0 \text{ V}, T_{DS} = 480 \text{ V}, T_J = 125^\circGate to Body Leakage CurrentV_{GS} = 480 \text{ V}, V_{DS} = 0 \text{ V}, T_{DS} = 480 \text{ V}, T_J = 125^\circGate Threshold VoltageV_{GS} = 10 \text{ V}, V_{DS} = 0 \text{ V}, T_{DS} = 10 \text{ V}, T_{DS} = 11 \text{ A}, TorsconductanceStatic Drain to Source On ResistanceV_{GS} = 10 \text{ V}, I_D = 11 \text{ A}, Torsconductance}Porward TransconductanceV_{DS} = 20 \text{ V}, I_D = 11 \text{ A}, Torsconductance}Input CapacitanceV_{DS} = 100 \text{ V}, V_{GS} = 0 \text{ F}, Torsfer Capacitance}Output CapacitanceV_{DS} = 380 \text{ V}, V_{GS} = 0 \text{ F}, Total Gate Charge at 10VGate to Drain "Miller" ChargeV_{CS} = 10 \text{ V}, Torsfer Capacitance}, Total Gate Charge at 10VGate to Drain "Miller" ChargeV_{CS} = 10 \text{ V}, Torsfer Capacitance}, Total Gate Charge at 10VCharacteristicsV_{DD} = 380 \text{ V}, I_D = 11 \text{ A}, Torsfer Capacitance}, Torsfer Capacitance}, Total Gate Charge at 10VCharacteristicsV_{DD} = 380 \text{ V}, I_D = 11 \text{ A}, Torsfer Capacitance}, Total Gate Charge at 10VCharacteristicsV_{DD} = 380 \text{ V}, I_D = 11 \text{ A}, Torsfer Capacitance}, Torsfer Cap$	ParameterTest ConditionsteristicsDrain to Source Breakdown VoltageBreakdown Voltage Temperature coefficient $I_D = 1 \text{ mA}, V_{GS} = 0 \text{ V}, T_J = 25^{\circ}\text{C}$ Breakdown Voltage Temperature coefficient $I_D = 1 \text{ mA}, \text{Referenced to } 25^{\circ}\text{C}$ Zero Gate Voltage Drain Current $W_{DS} = 480 \text{ V}, V_{GS} = 0 \text{ V}$ Gate to Body Leakage Current $V_{GS} = \pm 50 \text{ V}, V_{DS} = 0 \text{ V}$ Gate Threshold Voltage $V_{GS} = \pm 50 \text{ V}, V_{DS} = 0 \text{ V}$ eristicsGate Threshold Voltage $V_{GS} = 10 \text{ V}, I_D = 11 \text{ A}$ Forward Transconductance $V_{DS} = 20 \text{ V}, I_D = 11 \text{ A}$ Power of transconductanceVDS $= 100 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHZ}$ Output CapacitanceOutput Capacitance $V_{DS} = 380 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHZ}$ Effective Output Capacitance $V_{DS} = 380 \text{ V}, I_D = 11 \text{ A}, V_{GS} = 0 \text{ V}$ Total Gate Charge at 10V $V_{DS} = 380 \text{ V}, I_D = 11 \text{ A}, V_{GS} = 10 \text{ V}, V_{GS} = 0 \text{ V}$ Gate to Drain "Miller" Charge (Note 4) Equivalent Series Resistance (G-S)f = 1 \text{ MHZ}CharacteristicsTurn-On Rise Time $V_{DD} = 380 \text{ V}, I_D = 11 \text{ A}, V_{GS} = 10 \text{ V}, R_G = 4.7 \Omega$ (Note 4)Equivalent Series Resistance (G-S)f = 1 MHzCharacteristicsTurn-On Rise Time(Note 4) <td>$\begin{tabular}{ c c c c } \hline Parameter & Test Conditions & Min. \\ \hline eristics \\ \hline Prain to Source Breakdown Voltage \$\$ I_D = 1 mA, V_{GS} = 0 V, T_J = 25^{\circ}C\$ & 600 \$\$ I_D = 1 mA, V_{GS} = 0 V, T_J = 150^{\circ}C\$ & 650 \$\$ Breakdown Voltage Temperature \$\$ Coefficient \$\$ I_D = 1 mA, Referenced to 25^{\circ}C\$ & - \$\$ V_{DS} = 480 V, V_{GS} = 0 V\$ & - \$\$ V_{DS} = 480 V, V_{GS} = 0 V\$ & - \$\$ V_{DS} = 480 V, V_{DS} = 0 V\$ & - \$\$ V_{DS} = 480 V, V_{DS} = 0 V\$ & - \$\$ Or \$\$ V_{DS} = 480 V, V_{DS} = 0 V\$ & - \$\$ Or \$\$ V_{DS} = 480 V, V_{DS} = 0 V\$ & - \$\$ Or \$\$ Or \$\$ V_{GS} = 10 V, V_{DS} = 0 V\$ & - \$\$ Or \$\$ O$</td> <td>$\begin{tabular}{ c c c c c } \hline Parameter & Test Conditions & Min. Typ. \\ \hline eristics \\ \hline Prain to Source Breakdown Voltage & \$I_D = 1 mA, V_{GS} = 0 V, T_J = 25^{\circ}C & 600 & - \\ \$I_D = 1 mA, V_{GS} = 0 V, T_J = 150^{\circ}C & 650 & - \\ \hline Breakdown Voltage Temperature & \$I_D = 1 mA, Referenced to 25^{\circ}C & - & 0.68 \\ \hline Coefficient & \$V_{DS} = 480 V, V_{GS} = 0 V & - & - \\ \hline Caste to Body Leakage Current & \$V_{GS} = 480 V, T_J = 155^{\circ}C & - & - \\ \hline Gate to Body Leakage Current & \$V_{GS} = 480 V, T_J = 155^{\circ}C & - & - \\ \hline eristics & \$V_{DS} = 480 V, T_J = 125^{\circ}C & - & - \\ \hline eristics & \$V_{DS} = 480 V, T_J = 125^{\circ}C & - & - \\ \hline eristics & \$V_{DS} = 480 V, T_J = 125^{\circ}C & - & - \\ \hline eristics & \$V_{CS} = V_{DS}, I_D = 250 \mu A & 2.0 & 3 \\ \hline Static Drain to Source On Resistance & \$V_{GS} = 10 V, I_D = 11 A & - & 22 \\ \hline haracteristics & \$V_{DS} = 100 V, V_{CS} = 0 V, f = 1 MH & - & 22 \\ \hline haracteristics & \$V_{DS} = 100 V, V_{CS} = 0 V, f = 1 MH & - & 22 \\ \hline haracteristics & \$V_{DS} = 100 V, V_{CS} = 0 V, f = 1 MH & - & 22 \\ \hline haracteristics & \$V_{DS} = 100 V, V_{CS} = 0 V, f = 1 MH & - & 23 \\ \hline Output Capacitance & \$V_{DS} = 380 V, V_{CS} = 0 V, f = 1 MH & - & 43 \\ Output Capacitance & \$V_{DS} = 380 V, V_{CS} = 0 V, f = 1 MH & - & 43 \\ \hline total Gate Charge at 10V & \$V_{DS} = 380 V, I_D = 11 A, & - & 45 \\ \hline Gate to Source Gate Charge & \$V_{CS} = 10 V, R_G = 10 V, \\ \hline taracteristics & \$V_{CS} = 10 V, R_G = 4.7 \Omega & & 1 \\ \hline turn-On Delay Time & \$V_{CS} = 10 V, R_G = 4.7 \Omega & & 1 \\ \hline turn-On Flail Time & \$V_{CS} = 10 V, R_G = 4.7 \Omega & & 49 \\ \hline turn-Of Flail Time & \$V_{CS} = 10 V, R_G = 4.7 \Omega & & 49 \\ \hline turn-Of Flail Time & \$V_{CS} = 0 V, R_G = 4.7 \Omega & & - & 49 \\ \hline turn-Of Flail Time & \$V_{CS} = 10 V, R_G = 4.7 \Omega & & - & 49 \\ \hline turn-Of Flail Time & \$V_{CS} = 0 V, R_G = 4.7 \Omega & & - & 49 \\ \hline turn-Of Flail Time & \$V_{CS} = 0 V, R_G = 4.7 \Omega & & - & 49 \\ \hline turn-Of Flail Time & \$V_{CS} = 0 V, R_G = 4.7 \Omega & & - & 49 \\ \hline turn-$</td> <td>$\begin{tabular}{ c c c c c } \hline Parameter & Test Conditions & Min. Typ. Max. \\ \hline eristics \\ \hline eristics \\ \hline Prain to Source Breakdown Voltage \$\$ I_D = 1 mA, V_{GS} = 0 V, T_J = 25^{\circ}C\$ & 600 & - & - & \\ \hline I_D = 1 mA, V_{GS} = 0 V, T_J = 150^{\circ}C\$ & 650 & - & - & \\ \hline Breakdown Voltage Temperature \$\$ I_D = 1 mA, Referenced to 25^{\circ}C\$ & - & 0.68 & - & \\ \hline Coefficient \$\$ V_{DS} = 480 V, V_{GS} = 0 V\$ & - & - & 100 \\ \hline V_{DS} = 480 V, V_{GS} = 0 V\$ & - & - & 100 \\ \hline Gate to Body Leakage Current \$\$ V_{GS} = 480 V, V_{GS} = 0 V\$ & - & - & 1100 \\ \hline Gate to Body Leakage Current \$\$ V_{GS} = 450 V, V_{DS} = 0 V\$ & - & - & 1100 \\ \hline eristics \$\$ Cate Threshold Voltage \$\$ V_{GS} = V_{DS}, I_D = 250 \ \mu A\$ \$\$ 2.0 \$\$ 3\$ \$\$ 4.0 \\ \hline Static Drain to Source On Resistance \$\$ V_{GS} = 10 V, I_D = 11 A\$ \$\$ 0.140 \$\$ 0.165 \\ \hline Forward Transconductance \$\$ V_{DS} = 100 V, V_{GS} = 0 V, \$\$ 1 1 A\$ \$\$ 0.140 \$\$ 0.165 \\ \hline Forward Transconductance \$\$ V_{DS} = 100 V, V_{GS} = 0 V, \$\$ 1 1 A\$ \$\$ - \$\$ 22 \$\$ - \$\$ haracteristics \$\$ \$\$ \$\$ 100 \ V, D_S = 380 V, V_{GS} = 0 V, \$\$ 1 950 \$\$ - \$\$ \$\$ 0 \ Uput Capacitance \$\$ V_{DS} = 100 V, V_{GS} = 0 V\$ \$\$ 1 9 \ 1 1 A\$ \$\$ - \$\$ \$\$ 1 950 \$\$ - \$\$ \$\$ \$\$ \$\$ \$\$ 0 \ Uput Capacitance \$\$ V_{DS} = 380 V, V_{GS} = 0 V\$ \$\$ \$\$ 1 0 \ V, 0 \ S = 380 V, V_{GS} = 0 V\$ \$\$ \$\$ \$\$ \$\$ \$\$ \$\$ \$\$ \$\$ \$\$ \$\$ \$\$ \$\$</td>	$\begin{tabular}{ c c c c } \hline Parameter & Test Conditions & Min. \\ \hline eristics \\ \hline Prain to Source Breakdown Voltage $$ I_D = 1 mA, V_{GS} = 0 V, T_J = 25^{\circ}C$ & 600 $$ I_D = 1 mA, V_{GS} = 0 V, T_J = 150^{\circ}C$ & 650 $$ Breakdown Voltage Temperature $$ Coefficient $$ I_D = 1 mA, Referenced to 25^{\circ}C$ & - $$ V_{DS} = 480 V, V_{GS} = 0 V$ & - $$ V_{DS} = 480 V, V_{GS} = 0 V$ & - $$ V_{DS} = 480 V, V_{DS} = 0 V$ & - $$ V_{DS} = 480 V, V_{DS} = 0 V$ & - $$ Or $$ V_{DS} = 480 V, V_{DS} = 0 V$ & - $$ Or $$ V_{DS} = 480 V, V_{DS} = 0 V$ & - $$ Or $$ Or $$ V_{GS} = 10 V, V_{DS} = 0 V$ & - $$ Or $$ O$	$\begin{tabular}{ c c c c c } \hline Parameter & Test Conditions & Min. Typ. \\ \hline eristics \\ \hline Prain to Source Breakdown Voltage & $I_D = 1 mA, V_{GS} = 0 V, T_J = 25^{\circ}C & 600 & - \\ $I_D = 1 mA, V_{GS} = 0 V, T_J = 150^{\circ}C & 650 & - \\ \hline Breakdown Voltage Temperature & $I_D = 1 mA, Referenced to 25^{\circ}C & - & 0.68 \\ \hline Coefficient & $V_{DS} = 480 V, V_{GS} = 0 V & - & - \\ \hline Caste to Body Leakage Current & $V_{GS} = 480 V, T_J = 155^{\circ}C & - & - \\ \hline Gate to Body Leakage Current & $V_{GS} = 480 V, T_J = 155^{\circ}C & - & - \\ \hline eristics & $V_{DS} = 480 V, T_J = 125^{\circ}C & - & - \\ \hline eristics & $V_{DS} = 480 V, T_J = 125^{\circ}C & - & - \\ \hline eristics & $V_{DS} = 480 V, T_J = 125^{\circ}C & - & - \\ \hline eristics & $V_{CS} = V_{DS}, I_D = 250 \mu A & 2.0 & 3 \\ \hline Static Drain to Source On Resistance & $V_{GS} = 10 V, I_D = 11 A & - & 22 \\ \hline haracteristics & $V_{DS} = 100 V, V_{CS} = 0 V, f = 1 MH & - & 22 \\ \hline haracteristics & $V_{DS} = 100 V, V_{CS} = 0 V, f = 1 MH & - & 22 \\ \hline haracteristics & $V_{DS} = 100 V, V_{CS} = 0 V, f = 1 MH & - & 22 \\ \hline haracteristics & $V_{DS} = 100 V, V_{CS} = 0 V, f = 1 MH & - & 23 \\ \hline Output Capacitance & $V_{DS} = 380 V, V_{CS} = 0 V, f = 1 MH & - & 43 \\ Output Capacitance & $V_{DS} = 380 V, V_{CS} = 0 V, f = 1 MH & - & 43 \\ \hline total Gate Charge at 10V & $V_{DS} = 380 V, I_D = 11 A, & - & 45 \\ \hline Gate to Source Gate Charge & $V_{CS} = 10 V, R_G = 10 V, \\ \hline taracteristics & $V_{CS} = 10 V, R_G = 4.7 \Omega & & 1 \\ \hline turn-On Delay Time & $V_{CS} = 10 V, R_G = 4.7 \Omega & & 1 \\ \hline turn-On Flail Time & $V_{CS} = 10 V, R_G = 4.7 \Omega & & 49 \\ \hline turn-Of Flail Time & $V_{CS} = 10 V, R_G = 4.7 \Omega & & 49 \\ \hline turn-Of Flail Time & $V_{CS} = 0 V, R_G = 4.7 \Omega & & - & 49 \\ \hline turn-Of Flail Time & $V_{CS} = 10 V, R_G = 4.7 \Omega & & - & 49 \\ \hline turn-Of Flail Time & $V_{CS} = 0 V, R_G = 4.7 \Omega & & - & 49 \\ \hline turn-Of Flail Time & $V_{CS} = 0 V, R_G = 4.7 \Omega & & - & 49 \\ \hline turn-Of Flail Time & $V_{CS} = 0 V, R_G = 4.7 \Omega & & - & 49 \\ \hline turn-$	$\begin{tabular}{ c c c c c } \hline Parameter & Test Conditions & Min. Typ. Max. \\ \hline eristics \\ \hline eristics \\ \hline Prain to Source Breakdown Voltage $$ I_D = 1 mA, V_{GS} = 0 V, T_J = 25^{\circ}C$ & 600 & - & - & \\ \hline I_D = 1 mA, V_{GS} = 0 V, T_J = 150^{\circ}C$ & 650 & - & - & \\ \hline Breakdown Voltage Temperature $$ I_D = 1 mA, Referenced to 25^{\circ}C$ & - & 0.68 & - & \\ \hline Coefficient $$ V_{DS} = 480 V, V_{GS} = 0 V$ & - & - & 100 \\ \hline V_{DS} = 480 V, V_{GS} = 0 V$ & - & - & 100 \\ \hline Gate to Body Leakage Current $$ V_{GS} = 480 V, V_{GS} = 0 V$ & - & - & 1100 \\ \hline Gate to Body Leakage Current $$ V_{GS} = 450 V, V_{DS} = 0 V$ & - & - & 1100 \\ \hline eristics $$ Cate Threshold Voltage $$ V_{GS} = V_{DS}, I_D = 250 \ \mu A$ $$ 2.0 $$ 3$ $$ 4.0 \\ \hline Static Drain to Source On Resistance $$ V_{GS} = 10 V, I_D = 11 A$ $$ 0.140 $$ 0.165 \\ \hline Forward Transconductance $$ V_{DS} = 100 V, V_{GS} = 0 V, $$ 1 1 A$ $$ 0.140 $$ 0.165 \\ \hline Forward Transconductance $$ V_{DS} = 100 V, V_{GS} = 0 V, $$ 1 1 A$ $$ - $$ 22 $$ - $$ haracteristics $$ $$ $$ 100 \ V, D_S = 380 V, V_{GS} = 0 V, $$ 1 950 $$ - $$ $$ 0 \ Uput Capacitance $$ V_{DS} = 100 V, V_{GS} = 0 V$ $$ 1 9 \ 1 1 A$ $$ - $$ $$ 1 950 $$ - $$ $$ $$ $$ $$ 0 \ Uput Capacitance $$ V_{DS} = 380 V, V_{GS} = 0 V$ $$ $$ 1 0 \ V, 0 \ S = 380 V, V_{GS} = 0 V$ $$ $$ $$ $$ $$ $$ $$ $$ $$ $$ $$ $$ $

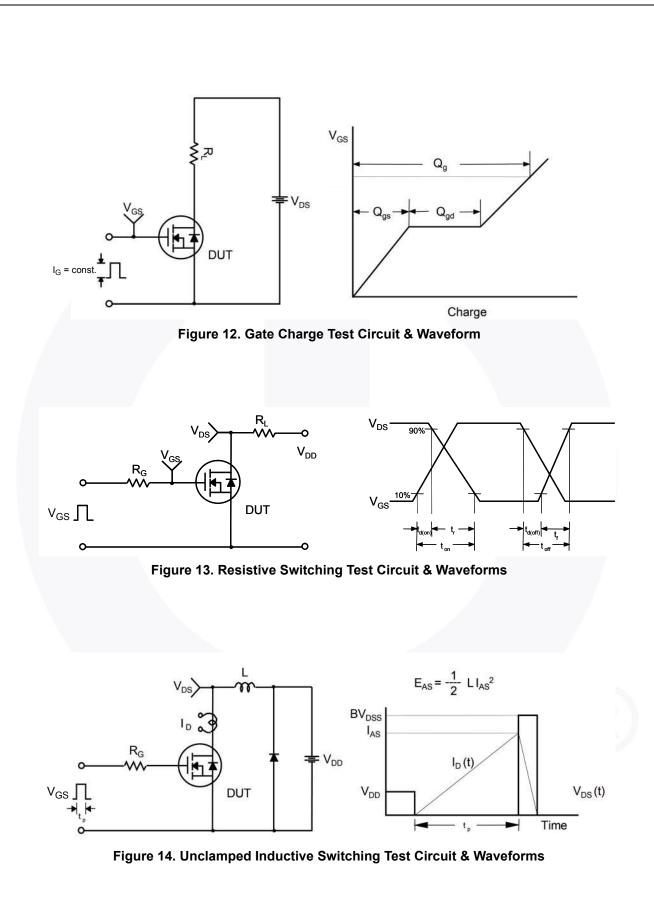
FCA22N60N — N-Channel SupreMOS[®] MOSFET



©2009 Fairchild Semiconductor Corporation FCA22N60N Rev. C2

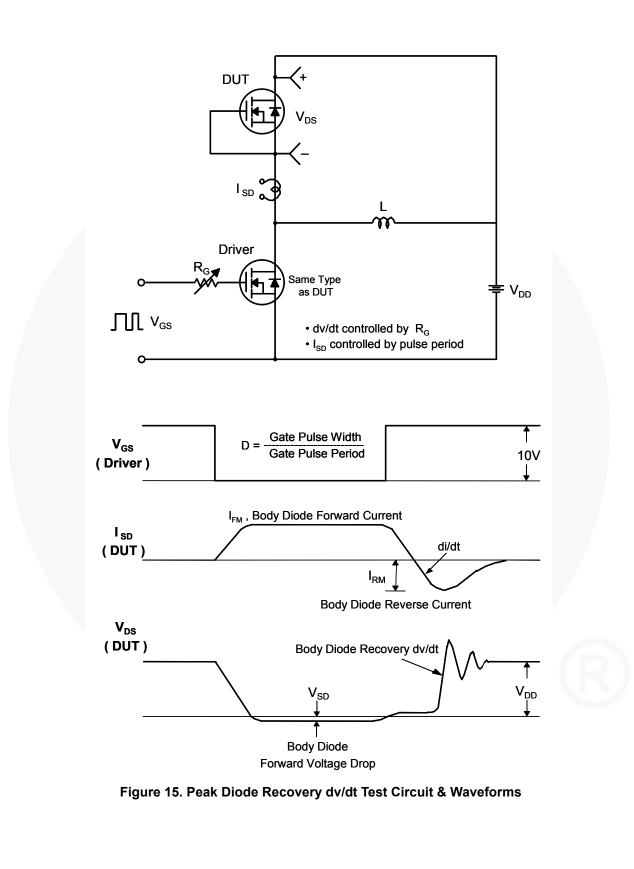


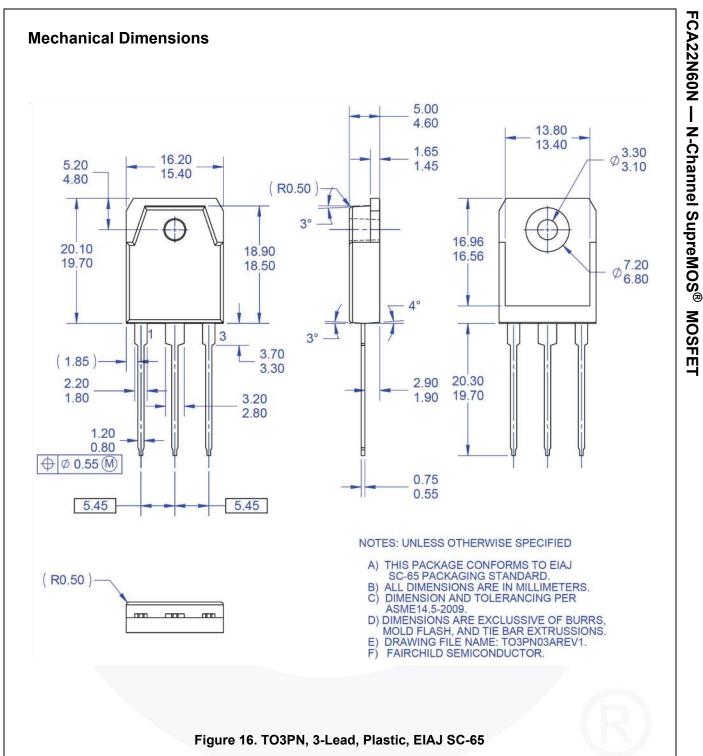
4



FCA22N60N — N-Channel SupreMOS[®] MOSFET

FCA22N60N — N-Channel SupreMOS[®] MOSFET





Package drawings are provided as a service to customers considering Fairchild components. Drawings may change in any manner without notice. Please note the revision and/or date on the drawing and contact a Fairchild Semiconductor representative to verify or obtain the most recent revision. Package specifications do not expand the terms of Fairchild's worldwide terms and conditions, specifically the warranty therein, which covers Fairchild products.

Always visit Fairchild Semiconductor's online packaging area for the most recent package drawings:

http://www.fairchildsemi.com/package/packageDetails.html?id=PN_TT3PN-003



ON Semiconductor and are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at <u>www.onsemi.com/site/pdf/Patent-Marking.pdf</u>. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor has against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death ass

PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT:

Literature Distribution Center for ON Semiconductor 19521 E. 32nd Pkwy, Aurora, Colorado 80011 USA Phone: 303-675-2175 or 800-344-3860 Toll Free USA/Canada Fax: 303-675-2176 or 800-344-3867 Toll Free USA/Canada Email: orderlit@onsemi.com N. American Technical Support: 800–282–9855 Toll Free USA/Canada Europe, Middle East and Africa Technical Support: Phone: 421 33 790 2910

Japan Customer Focus Center Phone: 81-3-5817-1050 ON Semiconductor Website: www.onsemi.com

Order Literature: http://www.onsemi.com/orderlit

For additional information, please contact your local Sales Representative

© Semiconductor Components Industries, LLC